

11/19/08

11-21-2008



103536117

ET

To the Director of the U. S. Patent and Trademark Office

documents or the new address(es) below.

1. Name of conveying party(ies):

Revera Incorporated

- Individual(s)
- General Partnership
- Corporation- State: Delaware
- Other _____
- Association
- Limited Partnership

Citizenship (see guidelines) _____

Additional names of conveying parties attached? Yes No

3. Nature of conveyance /Execution Date(s) :

Execution Date(s) 8/20/08

- Assignment
- Security Agreement
- Other _____
- Merger
- Change of Name

2. Name and address of receiving party(ies)

Additional names, addresses, or citizenship attached? Yes No

Name: Venture Lending & Leasing V. Inc.

Internal

Address: _____

Street Address: 2010 North First Street

City: San Jose

State: CA

Country: US Zip: 95131

- Association
- General Partnership
- Limited Partnership
- Corporation
- Other _____

Citizenship _____
Citizenship _____
Citizenship _____
Citizenship Maryland
Citizenship _____
If assignee is not domiciled in the United States, a domestic representative designation is attached: Yes No
(Designations must be a separate document from assignment)

4. Application number(s) or registration number(s) and identification or description of the Trademark.

A. Trademark Application No.(s)

B. Trademark Registration No.(s)

2,966,558; 2,966,561; 2,966,559; 3,299,597

Additional sheet(s) attached? Yes No

C. Identification or Description of Trademark(s) (and Filing Date if Application or Registration Number is unknown):

5. Name & address of party to whom correspondence concerning document should be mailed:

Name: Russell D. Pollack

Internal Address: _____

Street Address: 4 Embarcadero Center, Suite 4000

City: San Francisco

State: CA Zip: 94111

Phone Number: 415-981-1400

Fax Number: 415-777-4961

Email Address: _____

6. Total number of applications and registrations involved:

4

7. Total fee (37 CFR 2.6(b)(6) & 3.41) \$115.00

- Authorized to be charged to deposit account
- Enclosed

8. Payment Information:

11/21/2008 DKYRNE 00000011 2966558

Deposit Account Number 01 FCA5511 48.00 OP

02 FC:8522 75.00 OP

Authorized User Name _____

9. Signature:

[Signature] Signature

11/18/08

Date

Jeffrey T. Klugman
Name of Person Signing

Total number of pages including cover sheet, attachments, and document: 20

Documents to be recorded (including cover sheet) should be faxed to (571) 273-0140, or mailed to: Mail Stop Assignment Recordation Services, Director of the USPTO, P.O. Box 1450, Alexandria, VA 22313-1450

This Intellectual Property Security Agreement (this "Agreement") is made as of August 20, 2008, by and between REVERA INCORPORATED, a Delaware corporation ("Grantor"), and VENTURE LENDING & LEASING V, INC., a Maryland corporation, in its capacity as agent for itself and Silicon Valley Bank under the Loan Agreement (hereinafter defined) ("Secured Party").

RECITALS

A. Pursuant to a Loan and Security Agreement and Supplement of even date herewith (together, the "Loan Agreement") among Grantor, as borrower, and Secured Party, as agent for itself and Silicon Valley Bank as lenders ("Lenders"), Lenders have agreed to make certain advances of money and to extend certain financial accommodations to Grantor (the "Loans") in the amounts and manner set forth in the Loan Agreement. All capitalized terms used herein without definition shall have the meanings ascribed to them in the Loan Agreement.

B. Lenders are willing to make the Loans to Grantor, but only upon the condition, among others, that Grantor shall grant to Lenders and Secured Party for the benefit of Lenders a security interest in substantially all of Grantor's personal property whether presently existing or hereafter acquired. To that end, Grantor has executed in favor of Lenders the Loan Agreement granting a security interest in all Collateral, and is executing this Agreement with respect to certain items of Intellectual Property, in particular.

NOW, THEREFORE, THE PARTIES HERETO AGREE AS FOLLOWS:

1. Grant of Security Interest. As collateral security for the prompt and complete payment and performance of all of Grantor's present or future Obligations, Grantor hereby grants to Secured Party a security interest and mortgage to Secured Party, as security, in and to Grantor's entire right, title and interest in, to and under the following Intellectual Property, now owned or hereafter acquired by Grantor or in which Grantor now holds or hereafter acquires any interest (all of which shall collectively be called the "Collateral" for purposes of this Agreement):

(a) Any and all copyrights, whether registered or unregistered, held pursuant to the laws of the United States, any State thereof or of any other country; all registrations, applications and recordings in the United States Copyright Office or in any similar office or agency of the United States, and State thereof or any other country; all continuations, renewals, or extensions thereof; and any registrations to be issued under any pending applications, including without limitation those set forth on Exhibit A attached hereto (collectively, the "Copyrights");

(b) All letters patent of, or rights corresponding thereto, in the United States or any other country, all registrations and recordings thereof, and all applications for letters patent of, or rights corresponding thereto, in the United States or any other country, including, without limitation, registrations, recordings and applications in the United States Patent and Trademark Office or in any similar office or agency of the United States, any State thereof or any other country; all reissues, continuations, continuations-in-part or extensions thereof; all petty patents, divisionals, and patents of addition; and all patents to be issued under any such applications, including without limitation the patents and patent applications set forth on Exhibit B attached hereto (collectively, the "Patents");

(c) All trademarks, trade names, corporate names, business names, trade styles, service marks, logos, other source or business identifiers, prints and labels on which any of the foregoing have appeared or appear, designs and general intangibles of like nature, now existing or hereafter adopted or acquired, all registrations

and recordings thereof, and any applications in connection therewith, including, without limitation, registrations, recordings and applications in the United States Patent and Trademark Office or in any similar office or agency of the United States, any State thereof or any other country or any political subdivision thereof, and reissues, extensions or renewals thereof, and the entire goodwill of the business of Grantor connected with and symbolized by such trademarks, including without limitation those set forth on Exhibit C attached hereto (collectively, the “Trademarks”);

(d) Any and all claims for damages by way of past, present and future infringement of any of the rights included above, with the right, but not the obligation, to sue for and collect such damages for said use or infringement of the intellectual property rights identified above;

(e) All licenses or other rights to use any of the Copyrights, Patents or Trademarks, and all license fees and royalties arising from such use to the extent permitted by such license or rights;

(f) All amendments, renewals and extensions of any of the Copyrights, Trademarks or Patents; and

(g) All proceeds and products of the foregoing, including without limitation all payments under insurance or any indemnity or warranty payable in respect of any of the foregoing.

Notwithstanding the foregoing, the term “Collateral” as used in this Agreement shall not include any contracts, property rights or licenses to the extent that the grant of a security interest therein, or an assignment thereof, would be contrary to applicable law.

2. Covenants and Warranties. Grantor represents, warrants, covenants and agrees as follows:

(a) Grantor is now the sole owner of the Collateral, except for exclusive or non-exclusive licenses or sublicenses granted by Grantor in the ordinary course of business consistent with industry practice;

(b) During the term of this Agreement, Grantor will not transfer or otherwise encumber any interest in the Collateral, except for licenses or sublicenses granted by Grantor in the ordinary course of business consistent with industry practice or as otherwise permitted in the Loan Agreement;

(c) To its knowledge, each of the Patents is valid and enforceable, and no part of the Collateral has been judged invalid or unenforceable, in whole or in part, and no claim has been made that any part of the Collateral violates the rights of any third party;

(d) Grantor shall deliver to Secured Party within thirty (30) days of the last day of each fiscal quarter in which there is a change or update to the reported contents from the previous fiscal quarter, a report signed by Grantor, in form reasonably acceptable to Secured Party, listing any applications or registrations that Grantor has made or filed in respect of any patents, copyrights or trademarks and the status of any outstanding applications or registrations. Grantor shall promptly advise Secured Party of any material change in the composition of the Collateral, including but not limited to any subsequent ownership right of the Grantor in or to any Trademark, Patent or Copyright not specified in this Agreement;

(e) Grantor shall use reasonable commercial efforts to (i) protect, defend and maintain the validity and enforceability of the Trademarks, Patents and Copyrights, (ii) detect infringements of the Trademarks, Patents and Copyrights and promptly advise Secured Party in writing of material infringements detected, and (iii) not allow any material Trademarks, Patents or Copyrights to be abandoned, forfeited or dedicated to the public without the written consent of Secured Party, which consent shall not be unreasonably withheld;

(f) Grantor shall apply for registration (to the extent not already registered) with the United States Patent and Trademark Office or the United States Copyright Office, as applicable: (i) those intellectual property rights listed on Exhibits A, B and C hereto within thirty (30) days of the date of this Agreement; and (ii) those additional intellectual property rights developed or acquired by Grantor from time to time in connection with any product or service, prior to the sale or licensing of such product or the rendering of such service to any third party (including without limitation revisions or additions to the intellectual property rights listed on such Exhibits A, B and C), except, in each case, with respect to such rights that Grantor determines in its sole but reasonable commercial judgment need not be registered to protect its own business interests. Grantor shall, from time to time, execute and file such other instruments, and take such further actions as Secured Party may reasonably request from time to time to perfect or continue the perfection of Secured Party's interest in the Collateral. Grantor shall give Secured Party notice of all such applications or registrations; and

(g) Grantor shall not enter into any agreement that would materially impair or conflict with Grantor's obligations hereunder without Secured Party's prior written consent, which consent shall not be unreasonably withheld. Grantor shall not permit the inclusion in any material contract to which it becomes a party of any provisions that could or might in any way prevent the creation of a security interest in Grantor's rights and interests in any property included within the definition of the Collateral acquired under such contracts.

3. Further Assurances; Attorney in Fact.

(a) On a continuing basis, Grantor will, subject to any prior licenses, encumbrances, restrictions and Permitted Liens, make, execute, acknowledge and deliver, and file and record in the proper filing and recording places in the United States, all such instruments, including appropriate financing and continuation statements and collateral agreements and filings with the United States Patent and Trademark Office and the Register of Copyrights, and take all such action as may reasonably be deemed necessary or advisable, or as reasonably requested by Secured Party, to perfect Secured Party's security interest in all Copyrights, Patents and Trademarks and otherwise to carry out the intent and purposes of this Agreement, or for assuring and confirming to Secured Party the grant or perfection of a security interest in all Collateral.

(b) Grantor hereby irrevocably appoints Secured Party as Grantor's attorney-in-fact, with full authority in the place and stead of Grantor and in the name of Grantor, from time to time in Secured Party's discretion, to take any action and to execute any instrument which Secured Party deems necessary or advisable solely (i) to modify Exhibits A, B and C, hereof, as appropriate, of this Agreement without first obtaining Grantor's approval of or signature to such modification to include reference to any right, title or interest in any Copyrights, Patents or Trademarks acquired by Grantor after the execution hereof or to delete any reference to any right, title or interest in any Copyrights, Patents or Trademarks in which Grantor no longer has or claims any right, title or interest, (ii) to file, in its sole discretion, one or more financing or continuation statements and amendments thereto, relative to any of the Collateral without the signature of Grantor where permitted by law, and (iii) only after the occurrence and during the continuance of an Event of Default, to transfer the Collateral into the name of Secured Party or a third party to the extent permitted under the California Uniform Commercial Code.

(c) Secured Party agrees that it shall release its Lien on the Collateral (as such term is defined herein) on the terms and conditions set forth in the Supplement and to execute and deliver, at Grantor's sole cost and expense, all documents and instruments necessary to effectuate such release.

4. Events of Default. The occurrence of any of the following shall constitute an Event of Default under this Agreement:

(a) An Event of Default under the Loan Agreement; or

(b) Grantor breaches any warranty or agreement made by Grantor in this Agreement and, as to any breach that is capable of cure, Grantor fails to cure such breach within thirty (30) days of the sooner to occur of Grantor's receipt of notice of such breach from Secured Party or the date on which such breach first becomes known to Grantor.

5. Amendments. This Agreement may be amended only by a written instrument signed by both parties hereto, except for amendments to Exhibits A, B, and C as permitted under Section 3 hereof to be made by Secured Party alone.

6. Counterparts. This Agreement may be executed in two or more counterparts, each of which shall be deemed an original but all of which together shall constitute the same instrument.

Remainder of this page intentionally left blank; signature page follows

IN WITNESS WHEREOF, the parties hereto have executed this Agreement on the day and year first above written.

GRANTOR:

Address of Grantor:

REVERA INCORPORATED

810 Kifer Road
Sunnyvale, CA 94086
Attn: Chief Financial Officer

By: *T. Weld*
Name: Timothy D. Weld
Its: CFO

ORIGINAL

SECURED PARTY:

Address of Secured Party:

VENTURE LENDING & LEASING V, INC., as Agent

2010 North First Street, Suite 310
San Jose, CA 95131
Attn: Chief Financial Officer

By: _____
Name: _____
Its: _____

IN WITNESS WHEREOF, the parties hereto have executed this Agreement on the day and year first above written.

GRANTOR:

Address of Grantor:

REVERA INCORPORATED

810 Kifer Road
Sunnyvale, CA 94086
Attn: Chief Financial Officer

By: _____

Name: _____

Its: _____

SECURED PARTY:

Address of Secured Party:

VENTURE LENDING & LEASING V, INC., as Agent

2010 North First Street, Suite 310
San Jose, CA 95131
Attn: Chief Financial Officer

By: *M Maurice Werdegar*

Name: Maurice Werdegar

Its: President

ORIGINAL

EXHIBIT A

Copyrights

Description

Registration Number

Registration Date

None

EXHIBIT B

Patents

Description

Registration/Serial Number

Registration/Application Date

46109/0156
JTK/348886.1

TRADEMARK
REEL: 003892 FRAME: 0413

Summary of ReVERa I.P. Filings

Exhibit B

BSITZ FILE	COUNTRY	TITLE	STATUS	FILING DATE	SERIAL #	ISSUE DATE	PATENT NO.
7029P001	US	MULTICHANNEL CHARGED-PARTICLE ANALYZER	Issued	8/9/90	7565289	16-Jul-91	5032724
7029P001EP	EP	MULTICHANNEL CHARGED-PARTICLE ANALYZER - GERMANY	Issued	7/29/91	91112735.5	20-Dec-95	470478
7029P001EP	EP	MULTICHANNEL CHARGED-PARTICLE ANALYZER - EPO	Issued	7/29/91	911127355	20-Dec-95	0470478DE 69115589
7029P001GB	GB	MULTICHANNEL CHARGED-PARTICLE ANALYZER - GREAT BRITAIN	Issued	7/29/91	91112735.5	20-Dec-95	470478
7029P001JP	JP	MULTICHANNEL CHARGED-PARTICLE ANALYZER - JAPAN	Issued	7/29/91	3186501	15-Dec-00	3140094
7029P002	US	SCANNING AND HIGH RESOLUTION X-RAY PHOTOELECTRON SPECTROSCOPY AND IMAGING	Issued	9/29/92	7953429	24-May-94	5315113
7029P002DE	DE	SCANNING AND HIGH RESOLUTION X-RAY PHOTOELECTRON SPECTROSCOPY AND IMAGING - GERMANY	Issued	9/25/93	93113582.6	20-Mar-02	590308
7029P002EP	EP	SCANNING AND HIGH RESOLUTION X-RAY PHOTOELECTRON SPECTROSCOPY AND IMAGING - EPO	Issued	8/25/93	931135826	20-Mar-02	0590308DE 69331722.1 - 08
7029P002GB	GB	SCANNING AND HIGH RESOLUTION X-RAY PHOTOELECTRON SPECTROSCOPY AND IMAGING - GREAT BRITAIN	Issued	8/25/93	93113582.6	20-Mar-02	590308
7029P002JP	JP	SCANNING AND HIGH RESOLUTION X-RAY PHOTOELECTRON SPECTROSCOPY AND IMAGING - JAPAN	Issued	9/28/93	5263036	26-Nov-04	3621434
7029P002X	US	SCANNING AND HIGH RESOLUTION X-RAY PHOTOELECTRON SPECTROSCOPY AND IMAGING	Issued	2/25/94	8201912	22-Aug-95	5444242
7029P002XDE	DE	SCANNING IMAGING HIGH RESOLUTION ELECTRON SPECTROSCOPY - GERMANY	Issued	2/2/95	95101428.1	12-May-02	669635
7029P002XEP	EP	SCANNING IMAGING HIGH RESOLUTION ELECTRON SPECTROSCOPY - EPO	Issued	2/2/95	951014281	12-May-02	0669635DE 69526688

TRADEMARK

BSTZ FILE	COUNTRY	TITLE	STATUS	FILING DATE	SERIAL #	ISSUE DATE	PATENT NO.
7029P002XGB	GB	SCANNING IMAGING HIGH RESOLUTION ELECTRON SPECTROSCOPY - GREAT BRITAIN	Issued	2/2/95	95101428.1	12-May-02	669635
7029P002XJP	JP	SCANNING IMAGING HIGH RESOLUTION ELECTRON SPECTROSCOPY - JAPAN	Issued	2/24/95	737084	28-Jan-05	3641288
7029P004US	US	ANODE ASSEMBLY FOR GENERATING X-RAYS AND INSTRUMENT WITH SUCH ANODE ASSEMBLY	Issued	1/31/96	8593308	11-Feb-97	5602899
7029P003JP	JP	ANODE ASSEMBLY FOR GENERATING X-RAYS & INSTRUMENTS WITH SUCH ANODE ASSEMBLY - JAPAN	Pending	1/31/97	199719024		
7029P004US	US	CONTROL OF SURFACE POTENTIAL OF INSULATING SPECIMENS IN SURFACE ANALYSIS	Issued	11/12/97	8968454	23-Nov-99	5990476
7029P004DE	DE	CONTROL OF SURFACE POTENTIAL OF INSULATING SPECIMENS IN SURFACE ANALYSIS - GERMANY	Issued	11/21/97	97120498.7	3-Jul-02	848247
7029P004EP	EP	CONTROL OF SURFACE POTENTIAL OF INSULATING SPECIMENS IN SURFACE ANALYSIS - EPO	Issued	11/21/97	11277233	18-Jul-07	1 219 956
7029P004GB	GB	CONTROL OF SURFACE POTENTIAL OF INSULATING SPECIMENS IN SURFACE ANALYSIS - GREAT BRITAIN	Issued	11/21/97	97120498.7	3-Jul-02	848247
7029P004JP	JP	CONTROL OF SURFACE POTENTIAL OF INSULATING SPECIMENS IN SURFACE ANALYSIS - JAPAN	Issued	12/12/97	1997343242	12-Nov-04	3616714
7029P006XPGT	WG	SYSTEM AND METHOD FOR DEPTH PROFILING AND CHARACTERIZATION OF THIN FILMS - PCT	Pending	10/24/02	US0234137		
7029P006XTW	TW	SYSTEM AND METHOD FOR DEPTH PROFILING AND CHARACTERIZATION OF THIN FILMS - TAIWAN	Issued	10/25/02	91125043	1-Nov-04	1223060
7029P006XUS	US	SYSTEM AND METHOD FOR DEPTH PROFILING AND CHARACTERIZATION OF THIN FILMS	Pending	10/24/02	10293492		

BSTZ FILE	COUNTRY	TITLE	STATUS	FILING DATE	SERIAL #	ISSUE DATE	PATENT NO.
7029P007	US	NONDESTRUCTIVE CHARACTERIZATION OF THIN FILMS USING MEASURED BASIS SPECTRA	Issued	12/27/02	10330383	5-Oct-04	6800852
7029P009	US	NONDESTRUCTIVE CHARACTERIZATION OF THIN FILMS BASED ON ACQUIRED SPECTRUM	Issued	12/27/02	10330317	10-May-05	6891158
7029P009CN	CN	NONDESTRUCTIVE CHARACTERIZATION OF THIN FILMS BASED ON ACQUIRED SPECTRUM - CHINA	Pending	12/23/03	2.0038E+12		
7029P009EP	EP	NONDESTRUCTIVE CHARACTERIZATION OF THIN FILMS BASED ON ACQUIRED SPECTRUM - EP	Pending	12/23/03	38002309		
7029P009KR	KR	NONDESTRUCTIVE CHARACTERIZATION OF THIN FILMS BASED ON ACQUIRED SPECTRUM - KOREA	Pending	12/23/03	20057012492		
7029P009PCT	WO	NONDESTRUCTIVE CHARACTERIZATION OF THIN FILMS BASED ON ACQUIRED SPECTRUM - PCT	Pending	12/23/03	US03041372		
7029P009SG	SG	NONDESTRUCTIVE CHARACTERIZATION OF THIN FILMS BASED ON ACQUIRED SPECTRUM - SINGAPORE	Issued	12/23/03	2005046107	29-Jun-07	113997
7029P009TW	TW	NONDESTRUCTIVE CHARACTERIZATION OF THIN FILMS BASED ON ACQUIRED SPECTRUM - TAIWAN	Allowed	12/26/03	92137133		
7029P010	US	SEMICONDUCTOR SUBSTRATE PROCESSING METHOD AND APPARATUS	Pending	11/20/05	11040329		
7029P010EP	EP	A SEMICONDUCTOR SUBSTRATE PROCESSING METHOD AND APPARATUS	Pending	11/28/05	58477860		
7029P010EP	EP	A SEMICONDUCTOR SUBSTRATE PROCESSING METHOD AND APPARATUS - EP	Pending	11/28/05	70192588		
7029P010JP	JP	A SEMICONDUCTOR SUBSTRATE PROCESSING METHOD AND APPARATUS	Pending	11/28/05			
7029P010KR	KR	A SEMICONDUCTOR SUBSTRATE PROCESSING METHOD AND APPARATUS	Pending	8/17/07	20077018933		
7029P010PCT	WO	A SEMICONDUCTOR SUBSTRATE PROCESSING METHOD AND APPARATUS - PCT	Pending	11/28/05	PCTUS2005042863		

BSITZ FILE	COUNTRY	TITLE	STATUS	FLING DATE	SERIAL #	ISSUE DATE	PATENT NO.
7029P0131	US	ELECTRONIC DEVICE INCORPORATING A MULTILAYERED CAPACITOR FORMED ON A PRINTED CIRCUIT BOARD	Pending	12/22/04	1023271		
7029P012	US	FOCUSED ION BEAM COLUMN WITH ELECTRICALLY VARIABLE BLANKING APERTURE	Issued	3/20/96	8618599	10-Jun-97	5637879
7029P013	US	SAMPLE VESSEL	Expired	7/25/83	6516827	6-Aug-85	4532816
7029P014C	US	VACUUM-COMPATIBLE AIR-COOLED PLASMA DEVICE	Expired	2/26/86	6833575	21-Apr-87	4659899
7029P015C	US	ENERGY AND ANALYSIS DETECTION SYSTEM FOR SURFACE CHEMICAL ANALYSIS	Issued	6/24/87	7063806	12-Apr-88	4737639
7029P016	US	DIRECT IMAGING MONOCHROMATIC ELECTRON MICROSCOPE	Issued	6/5/87	7058437	7-Mar-89	4810880
7029P016EP	EP	DIRECT IMAGING MONOCHROMATIC ELECTRON MICROSCOPE - EPO	Issued	6/3/88	881089320	9-Aug-95	293924
7029P016JP	JP	DIRECT IMAGING MONOCHROMATIC ELECTRON MICROSCOPE, JAPAN	Issued	6/6/88	13763288	15-Aug-97	2685501
7029P016X	US	DIRECT IMAGING MONOCHROMATIC ELECTRON MICROSCOPE	Issued	11/8/88	7268440	21-Nov-89	4882487
7029P017	US	RESISIVE ANODE ENCODER TARGET AND METHOD PRODUCING BATHS CHARGED AND VISUAL IMAGES	Issued	10/6/88	7254442	18-Jun-92	5025144
7029P018	US	APPARATUS AND METHOD FOR LOCATING TARGET AREA FOR ELECTRON MICROANALYSIS	Issued	4/23/91	7690870	2-Jun-92	5118941
7029P018JP	JP	APPARATUS AND METHOD FOR LOCATING TARGET AREA FOR ELECTRON MICROANALYSIS, JAPAN	Pending	3/10/92	9614792		
7029P019	US	PARTICLE ANALYZER APPARATUS AND METHOD	Issued	10/23/89	7425568	7-Jul-92	5128543
7029P020	US	PLASMA ETCHING METHOD AND APPARATUS	Issued	9/6/90	7979331	1-Dec-92	5167748
7029P021	US	MECHANISM FOR POSITIONING A CARRIER	Issued	4/15/92	7869561	9-Feb-93	5184525
7029P021JP	JP	MECHANISM FOR POSITIONING A CARRIER, JAPAN	Pending	4/14/93	10975093		
7029P022	US	SUSPENSION SYSTEM FOR ISOLATING VIBRATIONS	Issued	12/17/91	7809691	25-May-93	5213301

BSTZ FILE	COUNTRY	TITLE	STATUS	FILING DATE	SERIAL #	ISSUE DATE	PATENT NO.
7029P0220P	JP	SUSPENSION SYSTEM FOR SOLICITING VIBRATIONS - JAPAN	Pending	10/13/92	29915992		
7029P023	US	APPARATUS FOR RETAINING AN ELECTRODE BY A MAGNETICALLY SHIELDED MAGNET	Issued	4/6/92	7863640	8-Jun-93	5218262
7029P0231P	JP	APPARATUS FOR RETAINING AN ELECTRODE BY A MAGNETICALLY SHIELDED MAGNET - JAPAN	Pending	4/5/93	10011693		
7029P024	US	METHOD OF COATING THERMOREVERSIBLE HEAT-THICKENING POLYACRYLAMIDES	Issued	10/8/92	7958249	11-Jul-95	5432345
7029P026	US	DETERMINING LAYER THICKNESS USING PHOTOELECTRON SPECTROSCOPY	Allowed	4/29/05	11118035		
7029P026GN	GN	DETERMINING LAYER THICKNESS USING PHOTOELECTRON SPECTROSCOPY - PCT	Pending	4/19/06			
7029P026EP	EP	DETERMINING LAYER THICKNESS USING PHOTOELECTRON SPECTROSCOPY - PCT	Pending	4/19/06	67508622		
7029P026JP	JP	DETERMINING LAYER THICKNESS USING PHOTOELECTRON SPECTROSCOPY - PCT	Pending	4/19/08			
7029P026KR	KR	DETERMINING LAYER THICKNESS USING PHOTOELECTRON SPECTROSCOPY - PCT	Pending	4/19/06			
7029P026PCT	WO	DETERMINING LAYER THICKNESS USING PHOTOELECTRON SPECTROSCOPY - PCT	Pending	4/19/06	PCTUS2006044945		
7029P027	US	TECHNIQUES FOR ANALYZING DATA GENERATED BY INSTRUMENTS	Issued	4/29/05	11118683	12-Jun-07	7231324
7029P027GN	GN	TECHNIQUES FOR ANALYZING DATA GENERATED BY INSTRUMENTS - PCT	Pending	4/19/06			
7029P027EP	EP	TECHNIQUES FOR ANALYZING DATA GENERATED BY INSTRUMENTS - PCT	Pending	4/19/06	67489906		
7029P027JP	JP	TECHNIQUES FOR ANALYZING DATA GENERATED BY INSTRUMENTS - PCT	Pending	4/19/06			
7029P027KR	KR	TECHNIQUES FOR ANALYZING DATA GENERATED BY INSTRUMENTS - PCT	Pending	4/19/06			
7029P027PCT	WO	TECHNIQUES FOR ANALYZING DATA GENERATED BY INSTRUMENTS - PCT	Pending	4/19/06	PCTUS2006044942		
7029P028	US	PHOTOELECTRON SPECTROSCOPY APPARATUS AND METHOD OF USE	Issued	7/15/08	7,399,963		
7029P028PCT	WO	PHOTOELECTRON SPECTROSCOPY APPARATUS AND METHOD OF USE - PCT	Pending	9/8/06	PCTUS2006034781		

BSTZ FILE	COUNTRY	TITLE	STATUS	FILING DATE	SERIAL #	ISSUE DATE	PATENT NO.
7029P029	US	METHOD AND SYSTEM FOR NON-DESTRUCTIVE DISTRIBUTION PROFILING OF AN ELEMENT IN A FILM	Allowed	8/12/08	7,411,188		
7029P028	US	METHOD AND SYSTEM FOR NON-DESTRUCTIVE DISTRIBUTION PROFILING OF AN ELEMENT IN A FILM	Pending	6/23/06	US2006024581		
7029P029Z	US	METHOD AND SYSTEM FOR NON-DESTRUCTIVE DISTRIBUTION PROFILING OF AN ELEMENT IN A FILM	Expired	7/11/05	60698367		
7029P032	US	DIAMOND ANODE	Pending	9/15/05	11228685		
7029P033	US	A METHOD AND APPARATUS FOR MEASURING THE THICKNESS OF A FILM UTILIZING WDS	Unfiled				
7029P034	US	A METHOD AND APPARATUS FOR MEASURING FILM THICKNESS UTILIZING ELECTRON BEAM X-RAY	Pending	10/30/07			
7029P035	US	CALIBRATING MULTIPLE PHOTOELECTRON SPECTROSCOPY SYSTEMS	Pending	3/30/06	11395189		
7029P036	US	METHOD AND SYSTEM FOR MEASUREMENT OF AIRBORNE MOLECULAR CONTAMINATION OF A SURFACE	Pending				
7029P037	US	METHOD AND SYSTEM FOR MEASURING AIRBORNE MOLECULAR CONTAMINATION OF A SURFACE	Pending	10/31/07			
7029P037	US	STRAIN MEASUREMENT IN SEMICONDUCTORS	Unfiled				
7029P037	US	STRAIN MEASUREMENT	Pending	10/29/07			
7029P038	US	DOT ANODE	Unfiled				
7029P038Z	US	DOT ANODE	Pending	11/14/07			
7029P039	US	DIAMOND ANODE DEVICES AND METHODS OF MAKING	Unfiled				
7029P040Z	US	COMBINED XRR AND XPS	Pending	10/29/07			

BSIZ FILE	COUNTRY	TITLE	STATUS	FILING DATE	SERIAL #	ISSUE DATE	PATENT NO.
7029P041Z	US	A METHOD FOR X-RAY MEASUREMENT IN XPS METROLOGY: THE USE OF FLUX-NORMALIZED XPS SIGNAL INTENSITIES TO ENHANCE THROUGHPUT AND PRECISION IN THICKNESS AND COMPOSITION MEASUREMENTS	Pending	4/29/08	61/048,811		
107 results displayed.							

TRADEMARK

REEL: 003892 FRAME: 0420

Description

Registration/Application Number

Registration/Application Date


Trademarks

EXHIBIT C

REVERA, INCORPORATED
007029

Exhibit C

TRADEMARK STATUS REPORT

Matter No.	MARK	Class	GOODS/SERVICES	SERIAL NO. FILING DATE	REG. NO. REG. DATE	Use & Renewal Dates	STATUS
T001 US	REVERA	9	Metrology systems comprised of computer hardware and x-ray equipment for measuring physical composition and thickness of thin films, for use in the semiconductor manufacturing process	78/ 332,899 11/ 25/ 03	2,966,558 7/ 12/ 05	Use: 7/ 12/ 11 Renewal: 7/ 12/ 15	Registered.
T002 US	REVERA Stylized 	9	Metrology systems comprised of computer hardware and x-ray equipment for measuring physical composition and thickness of thin films, for use in the semiconductor manufacturing process	78/ 332,929 11/ 25/ 03	2,966,561 7/ 12/ 05	Use: 7/ 12/ 11 Renewal: 7/ 12/ 15	Registered.
T003 US	RVX	9	Metrology systems comprised of computer hardware and x-ray equipment for measuring physical composition and thickness of thin films, for use in the semiconductor manufacturing process	78/ 332,907 11/ 25/ 03	2,966,559 7/ 12/ 05	Use: 7/ 12/ 11 Renewal: 7/ 12/ 15	Registered.
T005 US	VERAFLEX	9	Metrology systems comprised of computer hardware and x-ray equipment for measuring physical composition and thickness of thin films, for use in the semiconductor manufacturing process	78/ 762,824 11/ 29/ 05	3,299,597 9/ 25/ 07	Use: 9/ 25/ 13 Renewal: 9/ 25/ 17	Registered.
T005MDP Madrid Protocol	VERAFLEX	9	Metrology systems comprised of computer hardware and x-ray equipment for measuring physical composition and thickness of thin films, for use in the	USPTO Ref. No.: A0004835	887998 5/ 26/ 06	Renewal: 5/ 26/ 16	Registered.

REVERA, INCORPORATED
TRADEMARK STATUS REPORT

Matter No.	MARK	Class	Goods/Services	SERIAL NO. FILING DATE	REG. NO. REG. DATE	Use & Renewal Dates	STATUS
T005MDP- CN China	REVERA	9	Metrology systems comprised of computer hardware and x-ray equipment for measuring physical composition and thickness of thin films, for use in the semiconductor manufacturing process	5/26/06			Pending.
T005MDP- CTM European Community	REVERA	9	Metrology systems comprised of computer hardware and x-ray equipment for measuring physical composition and thickness of thin films, for use in the semiconductor manufacturing process		887998 5/26/06	Renewal: 5/26/16	Registered.
T005MDP- JP Japan	REVERA	9	Metrology systems comprised of computer hardware and x-ray equipment for measuring physical composition and thickness of thin films, for use in the semiconductor manufacturing process		887998 5/26/06	Renewal: 5/26/16	Registered.
T005MDP- KR Korea	REVERA	9	Metrology systems comprised of computer hardware and x-ray equipment for measuring physical composition and thickness of thin films, for use in the semiconductor manufacturing process		887998 5/26/06	Renewal: 5/26/16	Registered.
T005MDP- SG Singapore	REVERA	9	Metrology systems comprised of computer hardware and x-ray equipment for measuring physical composition and thickness of thin films, for use in the semiconductor manufacturing process		887998 5/26/06	Renewal: 5/26/16	Registered.

REVERA, INCORPORATED
TRADEMARK STATUS REPORT

Matter No.	MARK	Class	GOODS/SERVICES	SERIAL NO. FILING DATE	REG. NO. REG. DATE	Use & Renewal Dates	STATUS
T005TW Taiwan	VERAFLEX	9	Metrology systems for use in the semiconductor manufacturing process i.e. computer hardware and x-ray equipment for measuring physical composition and thickness of thin films	095027427 5/29/06	01264366 6/1/07	Renewal: 5/31/17	Registered.